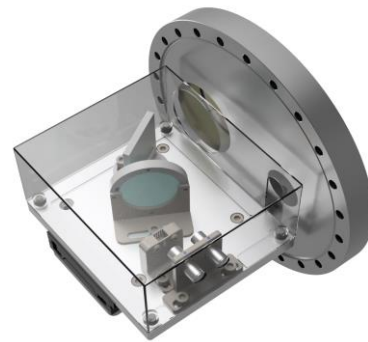
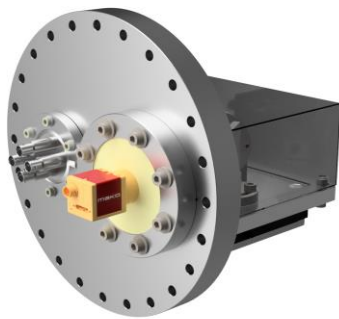


H + P SPECTROSCOPY SCIENTIFIC INSTRUMENTATION

nanoLIGHT

Integrated XUV spectrometer and beam profiler

This compact and versatile device makes XUV beam characterization easy: the nanoLIGHT combines the functionalities of an XUV spectrometer and an XUV beam profiler in one unit. It is quickly integrated into experimental setups: the entire device is mounted on a standard CF200 vacuum flange. Switching between operating modes or removal from the XUV beam path is completed within seconds.



Versatility

- two functionalities in one compact device
- fast switching between modes and transmission
- effortless integration
- integrated spectral filter insert
- integrated background light reduction
- compact and cost-effective

Efficiency and sensitivity

- wide spectral coverage: 10-80nm recorded simultaneously
- high overall efficiency
- large dynamic range due to MCP detection
- sensitivity adjustable, up to single photon counting regime
- low background noise

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iban • DE45 20041144 0 7899016 00
bic • COBADEHD044

Characteristics

- In-situ XUV spectrometer and beam profiler
- Compact footprint (16x17cm²)
- Cost-effective
- Quick mode switching
- Wavelength coverage 10 - 80nm, recorded simultaneously
- Insert for thin metal spectral filters
- Background light reduction jig
- Customizable according to user requirements

	XUV grating	other gratings
Spectrometer mode		
Wavelength [nm]	10 - 80	on request
Resolution [nm]	0.13 - 0.25	
Grating efficiency	~20%	
MCP efficiency	~20%	
Beam profiler mode		
Resolution [um]	100	

* Other configurations (spectral range, etc) available upon request.

Grating efficiency

